

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**  
Patent Application

Inventor(s): Fusao Ishii

Application No.: 10/814,082

Group Art Unit: 1756

Filed: 03/30/04

Examiner: C. Young

Title: METHODS FOR PATTERNING SUBSTRATES HAVING ARBITRARY AND UNEXPECTED DIMENSIONAL CHANGES

Form 1449**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
/CY/	A	6,559,924	05/06/03	Ina et al.	355	53	05/30/01
	B	6,529,262	03/04/03	Mei et al.	355	47	04/12/00
	C	6,312,134	11/06/01	Jain et al.	359	855	01/23/99
	D	5,652,645	07/29/97	Jain	355	53	07/24/95
	E	4,924,257	05/08/90	Jain	355	53	10/05/88
	F	5,285,236	02/08/94	Jain	355	53	09/30/92
	G	5,291,240	03/01/94	Jain	355	53	10/27/92
	H	5,710,619	01/20/98	Jain et al.	355	50	10/31/95
	I	5,721,606	02/24/98	Jain	355	53	09/07/95
	J	6,304,316	10/16/01	Jain et al.	355	53	10/22/98
	K	5,894,350	04/13/99	Hsieh et al.	356	399	06/12/98
	L	6,251,550	06/26/01	Ishikawa	430	22	07/07/99
	M	6,486,939	11/26/02	Lin	355	53	05/07/01
	N	6,121,626	09/19/00	Lin	250	548	09/17/98
	O	6,342,703	01/29/02	Koga et al.	250	548	10/20/99
	P	6,195,153	02/27/01	Shimizu	355	53	05/21/99
	Q	4,780,617	10/25/88	Umatate et al.	250	548	10/03/86
	R	5,493,402	02/20/96	Hirukawa	356	400	04/17/95
	S	5,936,712	08/10/99	Ito et al.	355	55	02/04/98
▼	T	6,261,728	07/17/01	Lin	430	30	10/19/98
	U	6,437,354	08/20/02	Nara et al.	250	548	07/05/00
/CY/	V	6,084,656	07/04/00	Choi et al.	355	71	08/28/98

**U.S. Published Patent Applications**

Examiner Initial	No.	Pub. No.	Pub. Date	Patentee	Class	Sub-class	Filing Date
/CY/	W	2003/0025979	02/06/03	Chan et al.	359	279	12/28/01
/CY/	X	2003/0025981	02/06/03	Ishikawa et al.	359	290	07/31/01

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation
	Y						Yes No

/Christopher Young/ (05/19/2007)

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	Z	
Examiner /Christopher Young/ (05/19/2007)		Date Considered 05/19/2007

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to applicant.